PIN FIN HEAT SINK

wakefield-vette

901 Series

Wakefield-Vette's 900 Series Heat Sinks for Chipset can match up to devices from:

Intel, Broadcom, Xilinx, TI, Motorola, ATI, AMD, Nvidia, Vishay, Powerex, Infineon, Microsemi, and many more.

These heat sinks are designed for air flow applications in the Telecom, Data Center, Networking, Cloud Computing, and many more Industries.

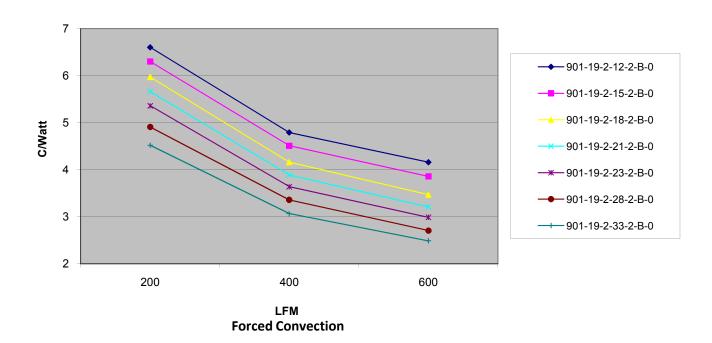
Material: AL 6063 Finish: Black Anodize RoHS





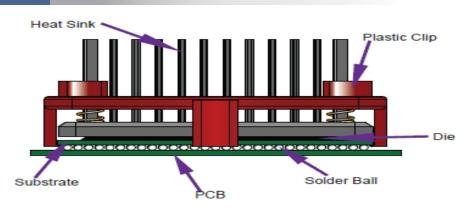
	HEIGHT	CHIP SIZE	NATURAL	FORCED CONVECTION (C/W)		
PART #	(mm)	(mm)	CONVECTION	200 LFM	400 LFM	600 LFM
901-19-2-12-2-B-0	12	19	12.74 C/W	6.6 C/W	4.79 C/W	4.16 C/W
901-19-2-15-2-B-0	15	19	12.05 C/W	6.3 C/W	4.51 C/W	3.86 C/W
901-19-2-18-2-B-0	18	19	11.35 C/W	5.97 C/W	4.16 C/W	3.47 C/W
901-19-2-21-2-B-0	21	19	10.66 C/W	5.66 C/W	3.89 C/W	3.21 C/W
901-19-2-23-2-B-0	23	19	10.55 C/W	5.36 C/W	3.64 C/W	2.99 C/W
901-19-2-28-2-B-0	28	19	10.27 C/W	4.91 C/W	3.36 C/W	2.71 C/W
901-19-2-33-2-B-0	33	19	9.99 C/W	4.52 C/W	3.07 C/W	2.49 C/W

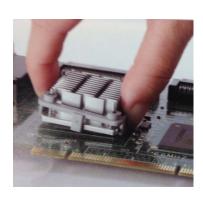
THERMAL PERFORMANCE:



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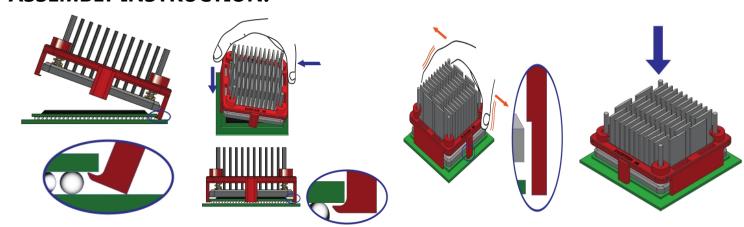
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Wakefield-Vette's heat sink assembles onto chip set using the space that is between the PCB and the substrate of the solder balls. The solder balls provide a minimal gap of .5mm to .7mm. Attachment feature is below a .4mm thickness. The clipping system will not interfere or damage chip. Contact area is the edge of chip.

ASSEMBLY INSTRUCTION:



Step 1: Hook the clip under one side of the BGA chip set.

Step 2: Rotate assembly down until opposite side clip engages substrate edge of BGA chip set.

Step 3: Make sure the sop rods are clearing from edges of BGA chip set.

Step 4: Press firmly down to make sure clips fully engage edges of chip set. Heat Sink should not move around easily.

Random Vibration Test

Frequency: 5 Hz to 500 Hz Acceleration: 3.13 grms P.S.D: 0.01 g2/HZ (5 Hz) 0.02 g2/HZ (20 Hz to 500 Hz)

Test Axis: X, Y, Z axis

Test Time: 10 mins (Each axis)

Total Test Time: 30 mins

SHOCK TEST SPECIFICATION:

Wave Form: Half sine wave

Acceleration: 50 g Duration Time: 11 ms

No. of Shock: Each axis 3 times Shock Direction: ±X, ±Y, ±Z axis Reliability & Communication

Testing Instruments